

Advance Technical Information

Trench Gate Power MOSFET

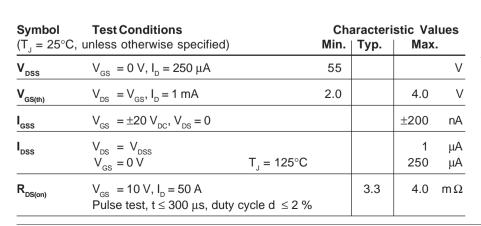
IXTQ 180N055T IXTA 180N055T IXTP 180N055T

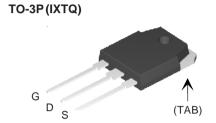
 $V_{DSS} = 55 V$ $I_{D25} = 180 A$ $R_{DS(on)} = 4.0 m\Omega$

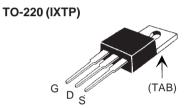
N-Channel Enhancement Mode



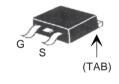
Symbol	Test Conditions	Maximum	Ratings
V _{DSS}	$T_J = 25^{\circ}\text{C to } 175^{\circ}\text{C}$ $T_J = 25^{\circ}\text{C to } 175^{\circ}\text{C}; R_{GS} = 1 \text{ M}\Omega$	55 55	V
V _{GSM}		±20	V
I _{D25} I _{DRMS} I _{DM}	$T_{\rm c} = 25^{\circ}{\rm C}$ External lead current limit $T_{\rm c} = 25^{\circ}{\rm C}$, pulse width limited by $T_{\rm JM}$	180 75 600	A A A
I _{AR}	$T_{\rm C} = 25^{\circ}{\rm C}$	75	А
E _{AS}	$T_{\rm c} = 25^{\circ}{\rm C}$	1.0	J
dv/dt	$I_{_{S}} \leq I_{_{DM}}, di/dt \leq 100 A/\mu s, V_{_{DD}} \leq V_{_{DSS}},$ $T_{_{J}} \leq 150^{\circ}C, R_{_{G}} = 10 \Omega$	3	V/ns
P_{D}	T _C = 25°C	360	W
T _J T _{JM} T _{stg}		-55 +175 175 -55 +150	°C °C °C
T _L	1.6 mm (0.062 in.) from case for 10 s Maximum tab temperature for soldering TO-263 package for 10s	300 260	°C °C
M _d	Mounting torque (TO-3P / TO-220)	1.13/10	Nm/lb.in.
Weight	TO-3P TO-220 TO-263	5.5 4 3	g g







TO-263 (IXTA)



G = Gate D = Drain S = Source TAB = Drain

Features

- International standard packages
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect

Advantages

- Easy to mount
- Space savings
- High power density

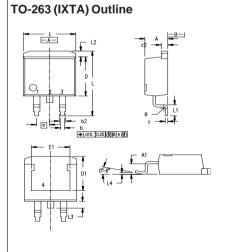


Test Conditions Characteristic Values Symbol (T₁ = 25°C, unless otherwise specified) Min. Max. Typ. 70 V_{DS} = 10 V; I_{D} = 50A, pulse test 90 S g_{fs} Ciss 5800 pF $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$ 1190 pF рF 138 Crss $\mathbf{t}_{\text{d(on)}}$ 37 ns $V_{GS} = 10 \text{ V}, V_{DS} = 40 \text{ V}, I_{D} = 40 \text{ A}$ 61 t, ns $R_c = 5 \Omega$ (External) 65 ns $\mathbf{t}_{\mathsf{d(off)}}$ 36 ns $\mathbf{Q}_{\mathrm{g(on)}}$ 160 nC \mathbf{Q}_{gs} $V_{GS} = 10 \text{ V}, V_{DS} = 30 \text{ V}, I_{D} = 90 \text{ A}$ 46 nC $\mathbf{Q}_{\underline{gd}}$ 47 nC ${\rm R}_{\rm thJC}$ 0.42 K/W (TO-3P) 0.21 K/W R_{thCK} (TO-220) 0.25 K/W

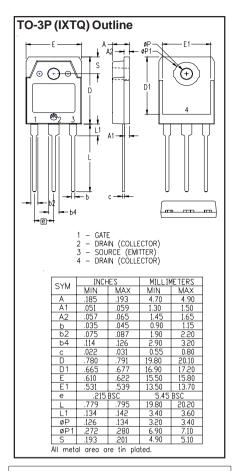
Source-Drain Diode

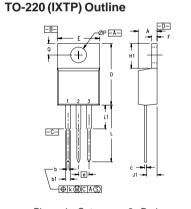
Characteristic Values (T = 25°C, unless otherwise specified)

Symbol	Test Conditions	Min.	typ.	Max.	,
I _s	V _{GS} = 0 V			180	Α
SM	Repetitive			600	Α
V _{SD}	$I_{_F} = 50~\text{A},~V_{_{GS}} = 0~\text{V},$ Pulse test, $t \leq 300~\mu\text{s},$ duty cycle d $\leq 2~\%$			1.2	V
t _{rr}	I _F = 25 A -di/dt = 100 A/μs		80		ns
\mathbf{Q}_{RM}	$V_R = 25 \text{ V}$		0.4		μС



Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
Α	4.06	4.83	.160	.190
A1	2.03	2.79	.080	.110
b	0.51	0.99	.020	.039
b2	1.14	1.40	.045	.055
С	0.46	0.74	.018	.029
c2	1.14	1.40	.045	.055
D	8.64	9.65	.340	.380
D1	7.11	8.13	.280	.320
Е	9.65	10.29	.380	.405
E1	6.86	8.13	.270	.320
е	2.54	BSC	.100	BSC
L	14.61	15.88	.575	.625
L1	2.29	2.79	.090	.110
L2	1.02	1.40	.040	.055
L3	1.27	1.78	.050	.070
L4	0	0.38	0	.015
R	0.46	0.74	.018	.029





Pins: 1 - Gate 2 - Drain

SYM	INCHES		MILLIMETERS		
2114	MIN	MAX	MIN	MAX	
Α	.170	.190	4.32	4.83	
b	.025	.040	0.64	1.02	
b1	.045	.065	1.15	1.65	
С	.014	.022	0.35	0.56	
D	.580	.630	14.73	16.00	
E	.390	.420	9.91	10.66	
е	.100 BSC		2.54 BSC		
F	.045	.055	1.14	1.40	
H1	.230	.270	5.85	6.85	
J1	.090	.110	2.29	2.79	
k	0	.015	0	0.38	
L	.500	.550	12.70	13.97	
L1	.110	.230	2.79	5.84	
ØΡ	.139	.161	3.53	4.08	
Q	.100	.125	2.54	3.18	

IXYS reserves the right to change limits, test conditions, and dimensions.



Fig. 1. Output Characteristics
@ 25°C

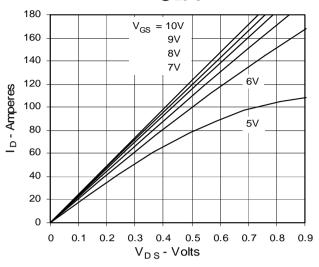


Fig. 3. Output Characteristics
@ 150°C

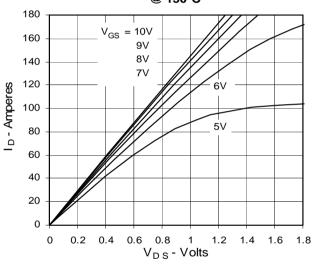


Fig. 5. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Drain Current

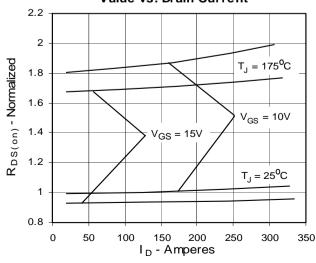


Fig. 2. Extended Output Characteristics
@ 25°C

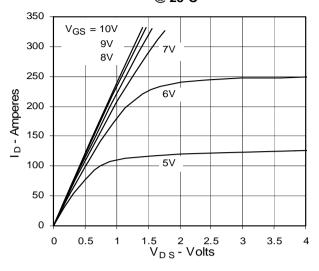


Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Junction Temperature

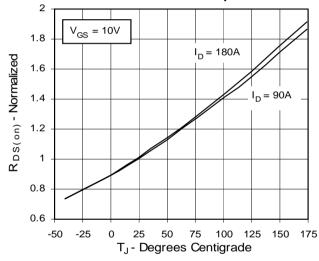


Fig. 6. Drain Current vs. Case Temperature

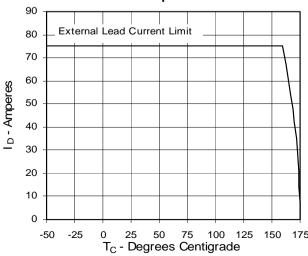




Fig. 7. Input Admittance

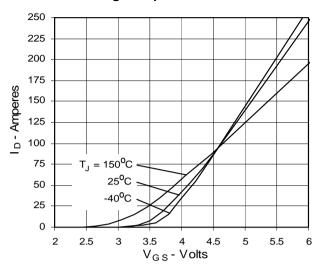


Fig. 9. Source Current vs. Source-To-Drain Voltage

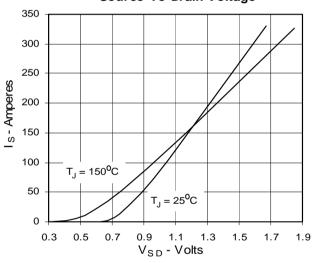


Fig. 11. Capacitance

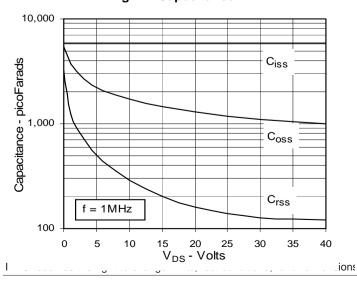


Fig. 8. Transconductance

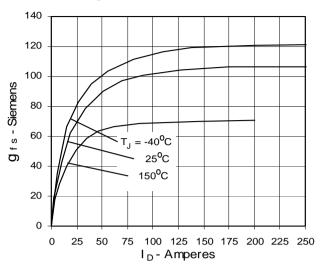


Fig. 10. Gate Charge

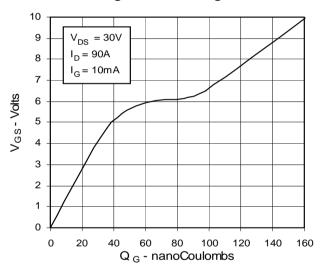


Fig. 12. Forward-Bias Safe Operating Area

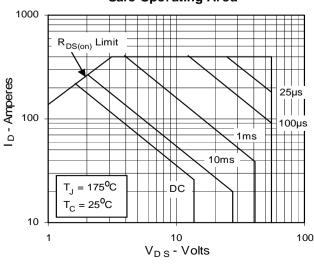




Fig. 13. Maximum Transient Thermal Resistance

